

# JUICE Instrument Workshop

Radiation Tolerant analogue / mixed signal technology  
survey and test vehicle design

Front-end readout ASIC technology study and development  
test vehicles for front-end readout ASICS

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Estec

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## Proposed activities

Radiation Tolerant analogue / mixed signal technology survey and test vehicle design  
Front-end readout ASIC technology study and development test vehicles for front-end readout ASICS

## Motivation

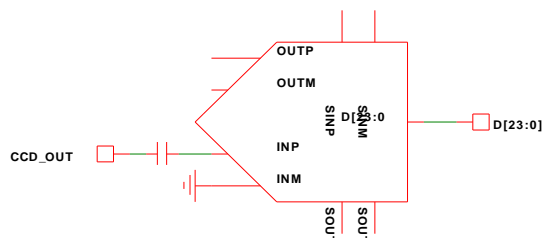
Investigation of the ASIC process technology to meet radiation requirement for front-end readout circuits and mixed signal application

## Mission/Activity adjustment

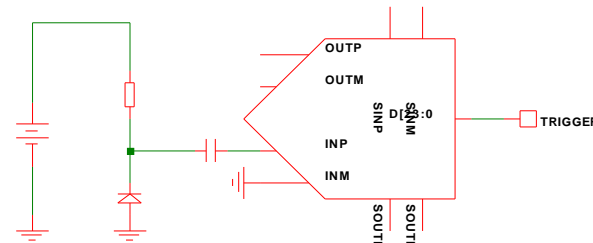
Lowered the radiation requirement  
Existing technology can meet the radiation requirement  
Activity has been redefined to increase the output T.R.L.

## Development of MF and HF Configurable Instrumentation ASIC

Radiation tolerance 300krad – Applications: 100kHz - 100MHz



CCD Readout



Radiation Detector

Radiation Spectrometer

ADC, DAC

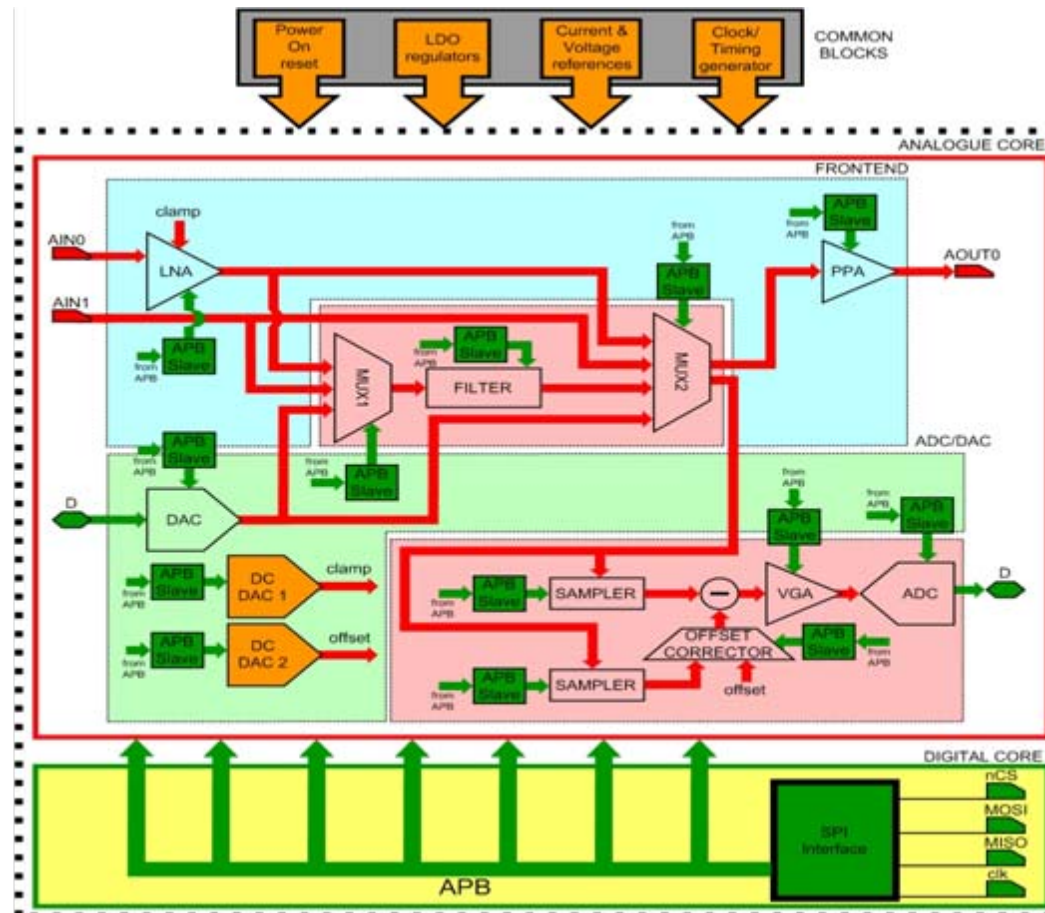
Filter – Low pass/Semi-Gaussian Shaper

Amplifier – Voltage/Current/Charge – Single ended/Differential

# Specification

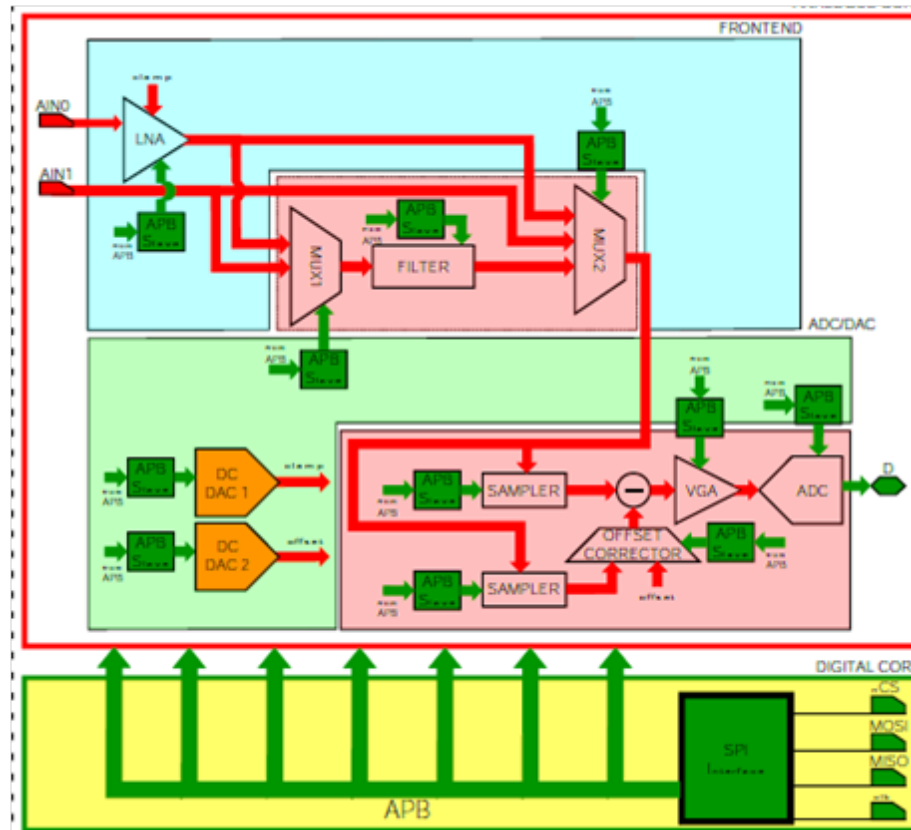
## Development of MF and HF Configurable Instrumentation ASIC

### Specification - Architecture



## Development of MF and HF Configurable Instrumentation ASIC

CCD signal processor



## Development of MF and HF Configurable Instrumentation ASIC

### CCD - signal processor

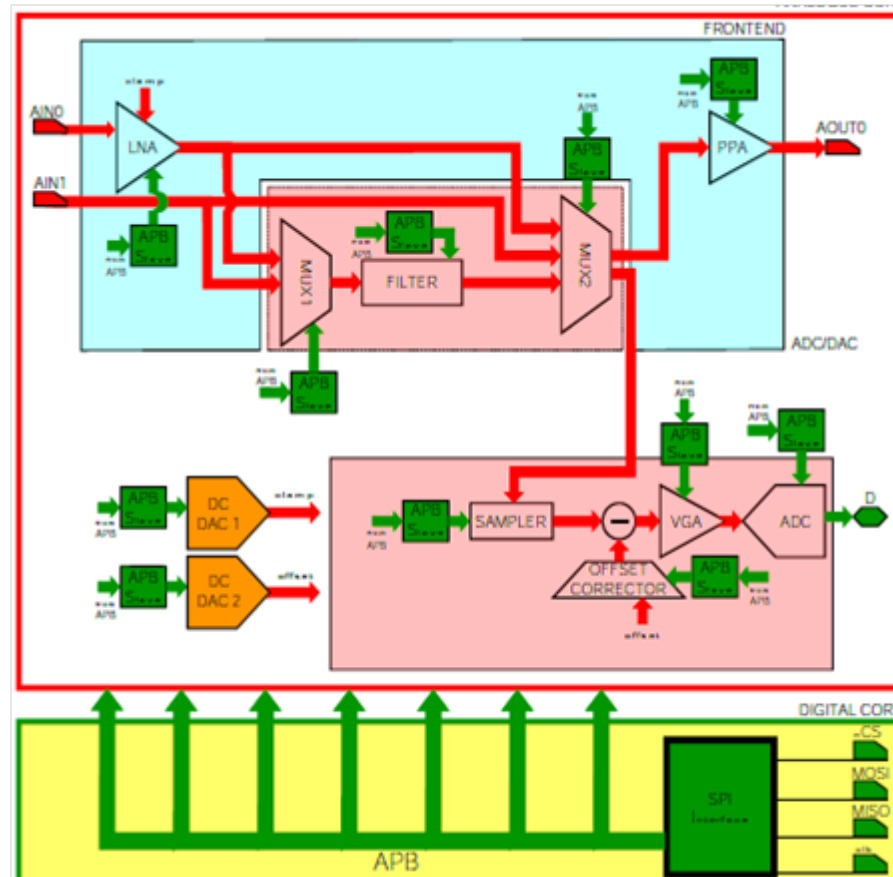
N°	Parameter	HF	MF	Unit
1	Input range	[0; 1.5]	[0; 1.5]	V
2	Input clamping	Configurable from 0 to 1.5	Configurable from 0 to 1.5	V
3	Input clamping step	100	100	mV
4	V/V gain (before filtering)	Configurable from -6 to 30	Configurable from -6 to 30	dB
6	V/V gain flatness	0.4	0.4	dB
7	Noise insertion (before filtering)	5	5	nV/ $\sqrt{\text{Hz}}$
8	Offset correction (after filtering)	Configurable from 10m to 1	Configurable from 10m to 1	V
9	Offset correction step (after filtering)	10m	10m	mV
10	V/V gain (before conversion)	Configurable from 0 to 30	Configurable from 0 to 30	dB
11	Sample rate	Configurable from 10 to 100	Configurable from 0.1 to 10	MHz
12	Effective N° of bits	12@10 10@100	17@0.1 14@1 12@10	Bits@MHz
13	ASIC current consumption	200	27	mA

# Specification

## Development of MF and HF Configurable Instrumentation ASIC

Radiation detector

Radiation spectrometer



## Development of MF and HF Configurable Instrumentation ASIC

### Radiation detector

N°	Parameter	HF	MF	Unit
1	ENC	50*	80*	$e_{rms}$
2	ENC slope	5.0*	1.6*	$e_{rms}/pF$
3	Range	200@0.2pF 20000@20pF	200@0.2pF 20000@20pF	fC
4	Peaking time for Gaussian shaper	[0.05; 1]	[0.1; 10]	$\mu s$
5	Peaking time accuracy for Gaussian shaper	5	5	%
6	Threshold level	[10; 1000]	[10; 1000]	mV
7	Threshold step	10	10	mV
8	Current consumption contribution of LNA and filter	70	70	mA



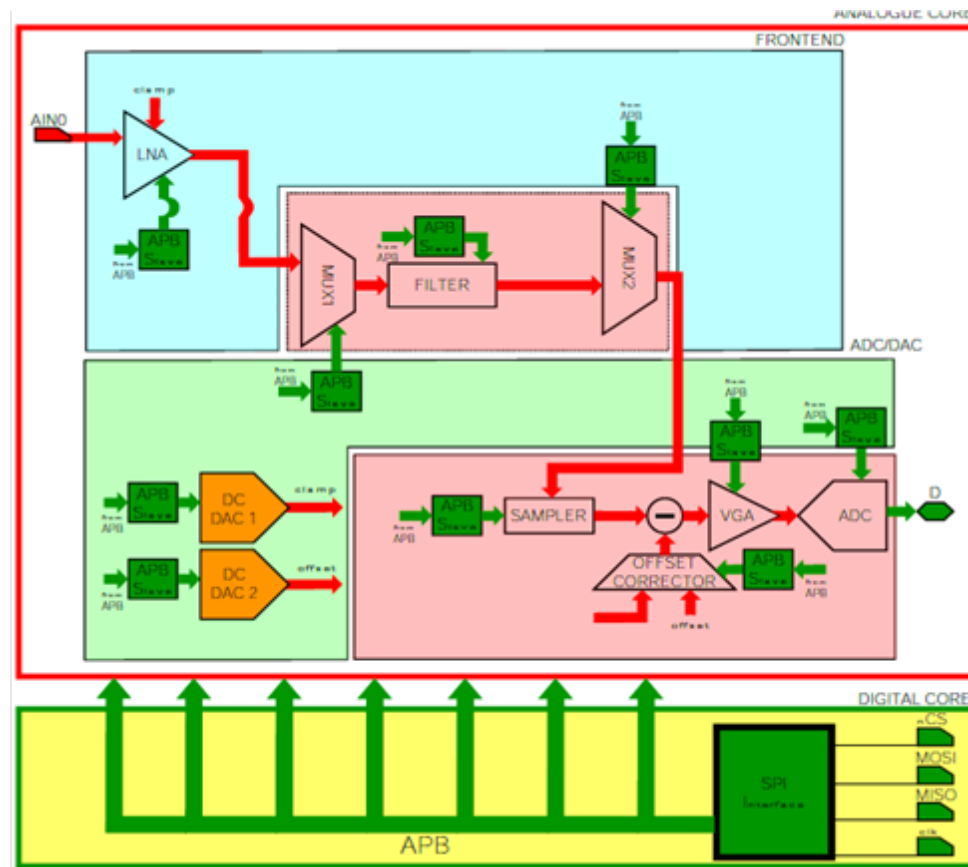
## Development of MF and HF Configurable Instrumentation ASIC

### Radiation spectrometer

N°	Parameter	HF	MF	Unit
1	ENC	50*	80*	$e_{rms}$
2	ENC slope	5*	1.6*	$e_{rms}/pF$
3	Range	200 @ 0.2pF 20000 @ 20pF	200 @ 0.2pF 20000 @ 20pF	fC
4	Peaking time for Gaussian shaper	[0.1; 10]	[0.1; 10]	$\mu s$
5	Peaking time accuracy for Gaussian shaper	5	5	%
6	Effective number of bits	12@10 10@100	17 @ 0.1 14 @ 1 12 @ 10	bits@MHz
7	Threshold level	[10; 1000]	[10; 1000]	mV
8	Threshold step	10	10	mV
9	Current consumption contribution of LNA and filter	200	4.5	mA

## Development of MF and HF Configurable Instrumentation ASIC

### ADC



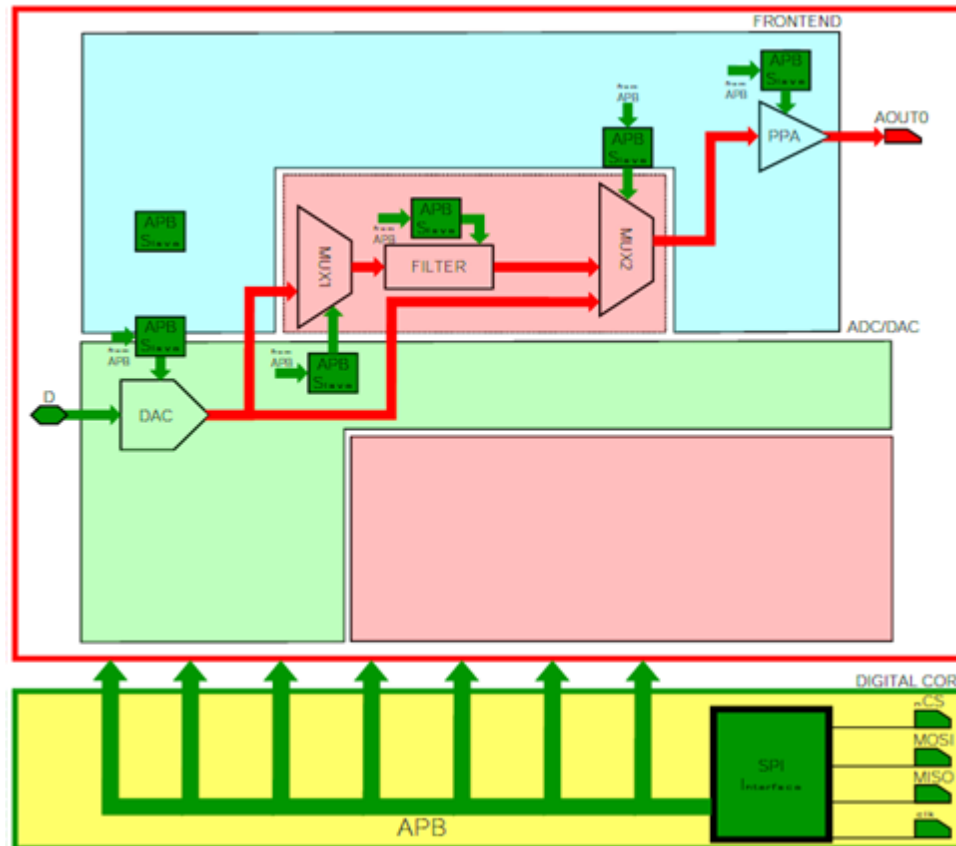
## Development of MF and HF Configurable Instrumentation ASIC

### ADC

N°	Parameter	HF	MF	Unit
1	Number of bits	15 @ 10 15 @ 100	19 @ 0.1 16 @ 1 14 @ 10	Bits @ MHz
2	Sample rate	[10; 100]	[0.1; 10]	MHz
3	Effective number of bits	12 @ 10 10 @ 100	17 @ 0.1 14 @ 1 12 @ 10	Bits @ MHz
4	Input range	2	2	V <sub>dpk</sub>
5	Maximum gain flatness	0.2	0.2	dB
6	Maximum gain stability	0.1	0.1	dB
7	Minimum THD	74@10 64@100	104@0.1 84@1 74@10	dB@MHz
8	Minimum SFDR	74@ 10 64 @ 100	104 @ 0.1 84 @ 1 74 @ 10	dB@ MHz
9	Current consumption contribution of ADC block	250 @ 100	2 @ 0.1 4 @ 1 20 @ 10	mA@MHz

## Development of MF and HF Configurable Instrumentation ASIC

### DAC



## Development of MF and HF Configurable Instrumentation ASIC

### DAC

N°	Parameter	HF	MF	Unit
1	Number of bits	15 @ 10 15 @ 100	19@0.1 16@1 14@10	Bits @ MHz
2	Sample rate	[100]	[0.1; 10]	MHz
3	Effective number of bits	12 @ 10 9 @ 100	17@0.1 14@1 12@10	Bits @ MHz
4	Input range	2	2	Vdpk
5	Maximum gain flatness	4	0.2	dB
6	Maximum gain stability	0.1	0.1	dB
7	Minimum THD	72@10 57@100	124@0.1 104@1 84@10	dB@MHz
8	Minimum SFDR	74 @ 10 59 @ 100	124 @ 0.1 104 @ 1 84 @ 10	dB@ MHz
9	Current consumption contribution of DAC block	60 @ 100	1 @ 0.1 2 @ 1 20 @ 10	mA@MHz

KO - 17-09-2010

ADR - 29-06-2011

## Consortium

1. Arquimea – Madrid
2. CSIC (IMB-CNM) – Barcelona
3. CSIC (IMSE-CNM)– Seville
4. UPC - University of Catalunya – Barcelona
5. UC3M – University of Carlos III – Madrid

## System

MF ADC/DAC

HF ADC/DAC

MF/HF Front-end

Digital

ARQUIMEA



## Circuit verification of ASIC blocks

Low noise amplifier

Output amplifier

ADC - HF

DAC – HF

Common blocks : Bandgap – Current/Voltage reference generator

## Circuit design of ASIC blocks

ADC – MF

DAC - MF

Filter – MF/HF

Sampler





Performance specification review

ASIC specification - available for review

Application review

Model of ASIC developed (VerilogA) – available for simulation

Applications covered

- 1) ADC
- 2) DAC
- 3) Amplifier
- 4) Filter
- 5) Radiation detector
- 6) Radiation spectrometer
- 7) CCD processor

## Performance specification

Provide e-mail to ESA to obtain a copy

## Application review

Sign a NDA with Arquimea to obtain a copy

Provide application feedback to ESA

Demonstration of the Model at JUICE Instrument Workshop

## Test-vehicle testing

Inform ESA about the intention to participate in the testing

Provide information on the test application

**THANK YOU**

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